

COLUTAv4 Update

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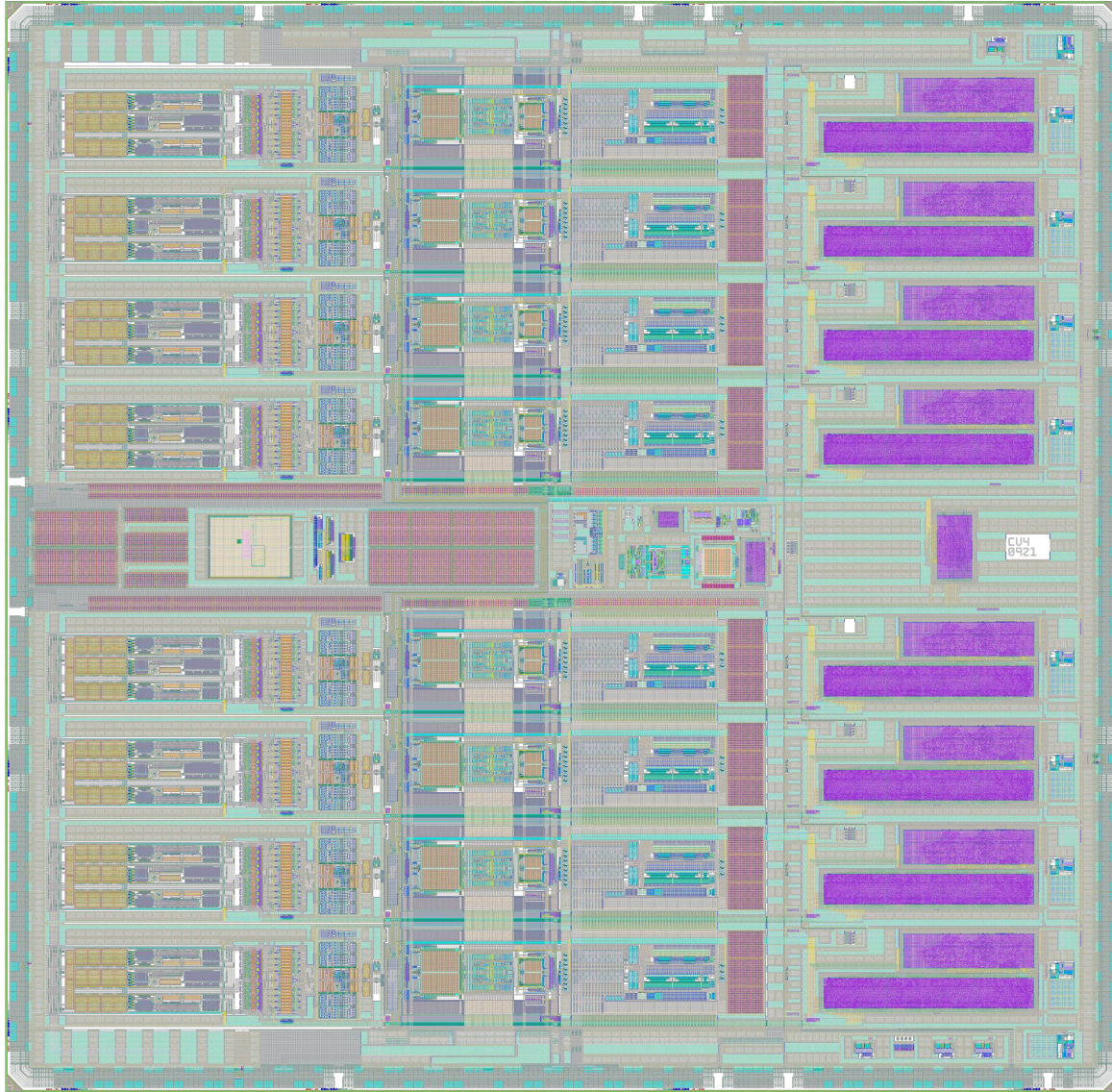
on behalf of the COLUTA Team

October 6, 2021

Introduction

- COLUTAv4 Status at submission
- Progress on packaging
- Progress on production test setup

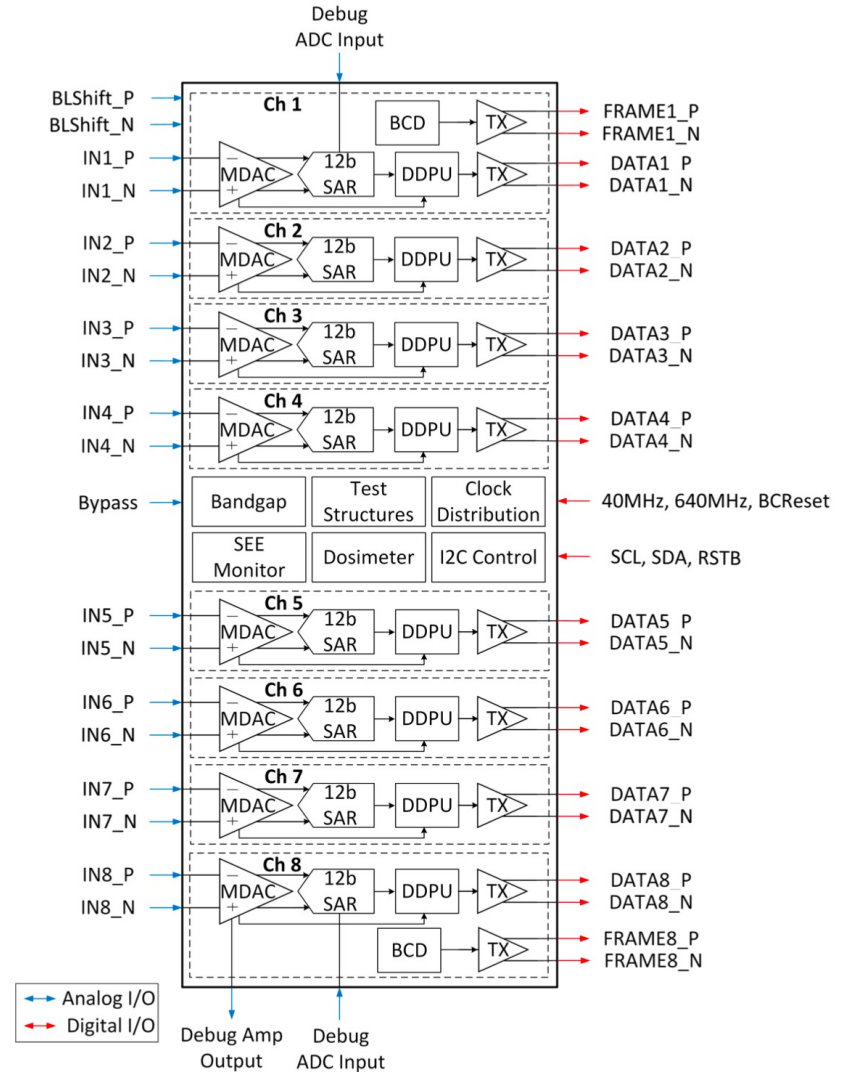
COLUTAv4



- Submitted Sep. 1
- TSMC 65nm LP 1.2 V
- 5.584 x 5.456 mm²
- 100 I/O & 366 bondpads
- 4.3 million transistors

Prototype:

- 8 (identical) channel 15b A/D
 - MDAC+SAR+DDPU
- Seamless interface to PA/SH chips
- Digital outputs, Clock signals, BC resets, and Controls are IpGBT compatible
- BC ID in the frame output
- On-chip band-gap derives all required analog voltages



COLUTAv4 Modifications

Several modifications from COLUTAv3 (following PDR recommendations)

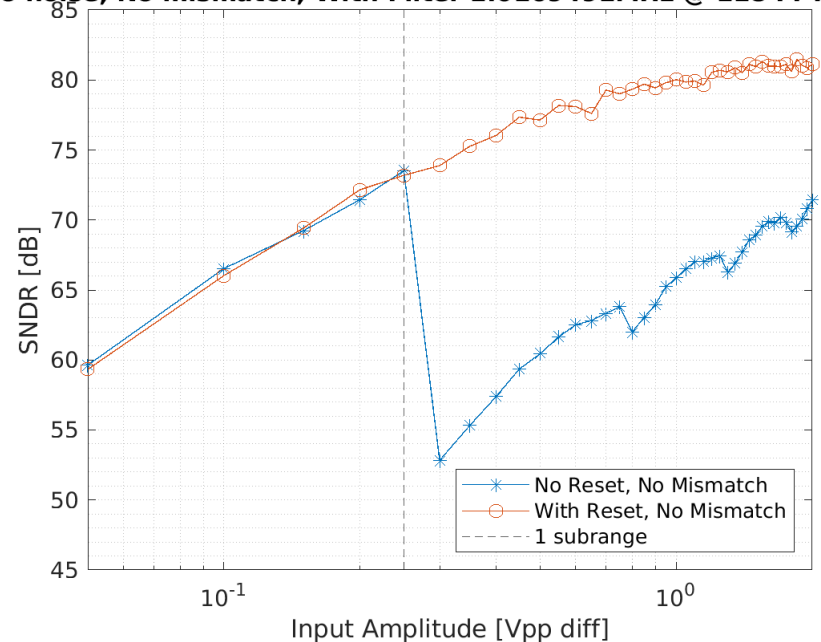
- Full discussion see Ray Xu's [talk](#) from Sep. 2 Phase-2 On-detector Mtg.
- **Analog settling** : Non-linearity as signal enters different MDAC subranges.
 - Mitigation - Extra (optional) clock phase was added into the MDAC to reset the sampling capacitor.
- **Analog settling** : Parasitic resistance results in insufficient reset leading to nonlinearity.
 - Mitigation - Reroute MDAC circuitry to different metal layers. Verify in R+C+CC simulation.
- **Digital correction** : If the analog range was less than the correct 2^n factor then would have a discontinuity.
 - Mitigation - A sign bit was added to the MDAC correction for additional redundancy.
- **I2C**: "NO-ACK" systematically observed in radiation test board (and simulation) due to arbitrary timing relation between SCL and state machine's on-chip 40 MHz clock.
 - Mitigation - Schmitt trigger I/O pads used. CERN Microelectronics Group recognizes the issues and now strongly recommends Schmitt trigger for I/O pads.
- **SEE**: Further SEE mitigation in digital blocks.
 - Mitigation - Discussions with CERN CHIPS team: TMRG and new synthesis/P&R scripts were used in CV4. Enforces > 15 um linear distance spacing of redundant logic

COLUTAv4 Simulation

- **Simulation “breadth”:** simulation should mimic measurement procedure.
 - Calibration simulation with on-chip digital arithmetic
 - Sine wave measurement with on-chip digital arithmetic
 - I2C functionality; Signal-in → signal-out
 - Depending on simulation goal, digital blocks may be simulated at the transistor level
- **Simulation “depth”:** check sensitivity to R+C+CC parasitics.
 - Digital blocks: behavioral simulation → extracted P&R simulation
 - Analog blocks: schematic simulation → extracted R+C+CC simulation
- **Putting it all together:**
 - Full-chip extraction simulation possible with careful control of the design hierarchy.

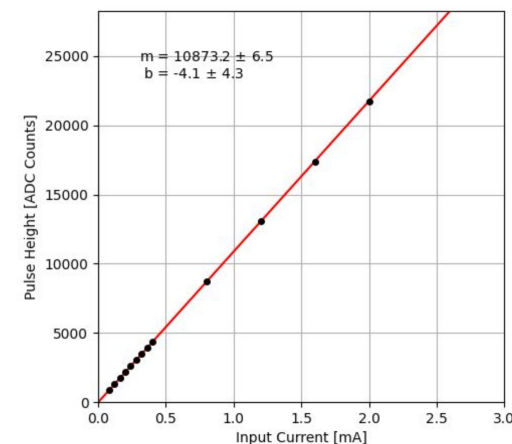
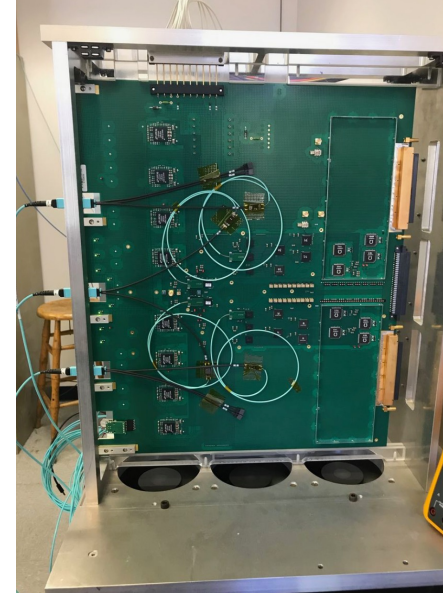
Example: Pin-point simulation for analog settling

SNDR vs Input Amplitude, Quantized
No noise, No mismatch, With Filter 1.0169491MHz @ 118 FFT point

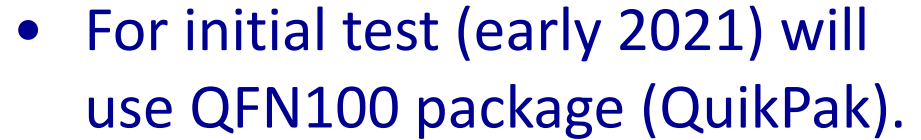


- Run **with fix (red)** and **w/o fix (blue)**. Some simulation features left out (i.e. transient noise) for efficiency.
- Simulation mimics measurement procedure, closes loop between measurements (calibration, data acquisition).

Integration



- PDR recommendation: Verify performance over power supply range $1.2 \text{ V} \pm 10\%$
 - Design choice to comprising maximizing full range while keeping transistors in saturation at nominal VDD of 1.2 V
 - maintain a fixed headroom (100 mV) w.r.t. VDD and GND.
 - **Impact:** PA/S and ADC should share a common 1.2V LDO to maintain the same full range (to avoid issues with radiation-induced drift in VDD). LDO output should be heavily filtered.
- PDR recommendation: Characterize PA/S+ADC
 - Used 32 ch. Slice Test Board (top right) to measure pulse shapes, energy/time resolution, INL (bottom right).
 - Many measurements done. See Andrew Smith's [talk](#) today.
 - Studied PA/S ADC interface in simulation (see Mietek's [talk](#)) and further transmission line simulations.



- Pinout prepared.
- Documented in (draft) datasheet.

- Includes SC bit assignments. (I2C)
- *And* data output format (Frame, modes)

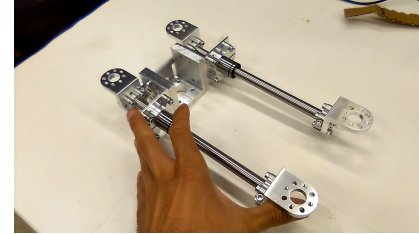
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Testing

Preparing now for production testing of 80k chips.

- Coordinating plans between interested groups (UT Austin, Saclay and Nevis). See [Sep. 30 Phase-2 ADC meeting](#).
 - **Austin:** Assembling robotic arm setup. In contact with Lund ALICE group (“SAMPA” robot). Interfacing existing test software to automate measurements.
 - **Saclay:** Experience with COLUTAv2 testboard and software. Existing “Pacman” automated robotic ASIC testbench.
 - **Nevis:** Existing test setups, including Slice test board.

UT Austin:

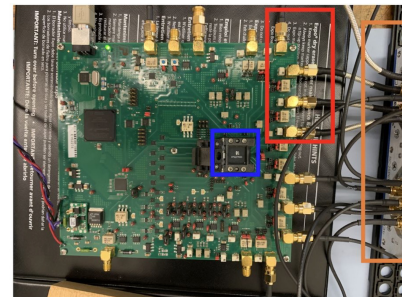


Yamaha
YK500XGL

Saclay:



Nevis:



Socket + ASIC
Programmable Switch
MDAC Channels (5-8)

Closing Remarks

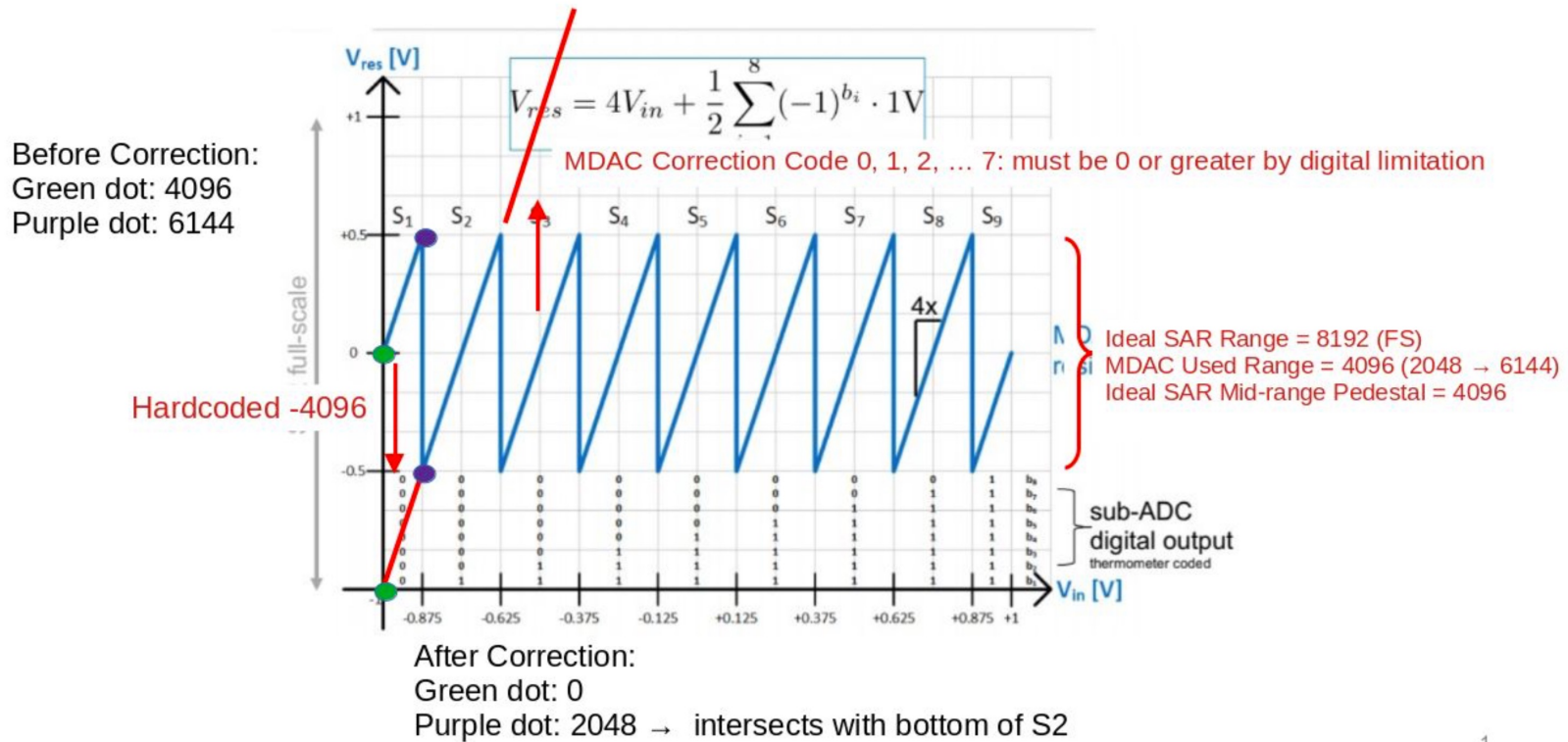
- COLUTAV4 builds on the successes of previous versions
 - Eight MDAC+SAR channels; final prototype ADC following series of 3 pre-prototypes
 - $5.584 \times 5.456 \text{ mm}^2$; 4.3 million transistors
- Largest and most complex chip to date in the COLUTA group
 - Most extensive simulation & verification effort so far.
- We look forward to testing V4!
 - Submitted Sept 1st
 - Chip dies expected back early December of this year.
- Many efforts happening in parallel (packaging, testing, firmware, software)
- We look forward to your comments.

BACKUP

Modification: Digital Correction

- Ideal case: analog range is exactly equal to the radix-2 designed values

Ideal DDPU Correction, No Redundancy

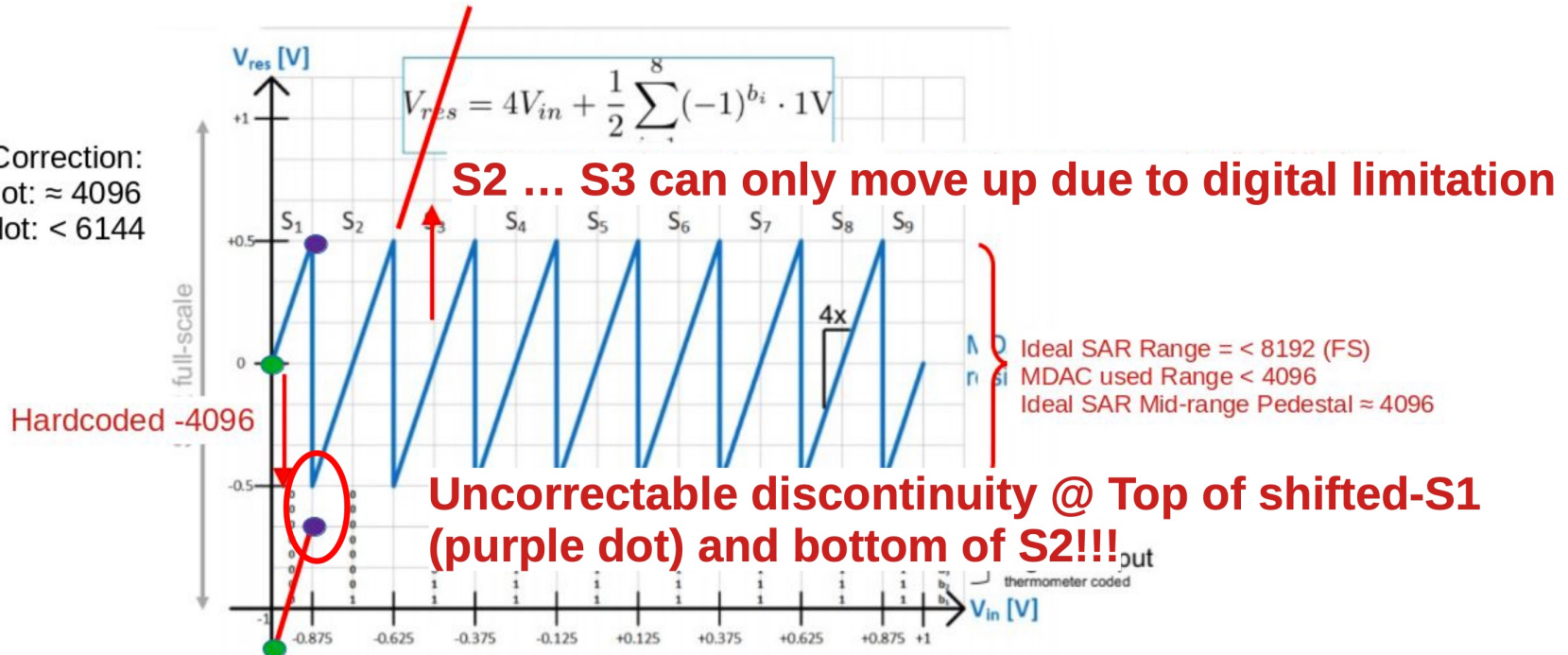


Modification: Digital Correction

- Scenario: analog range is slightly less than the radix-2 designed values

Actual DDPU Correction, No Redundancy

Before Correction:
Green dot: ≈ 4096
Purple dot: < 6144



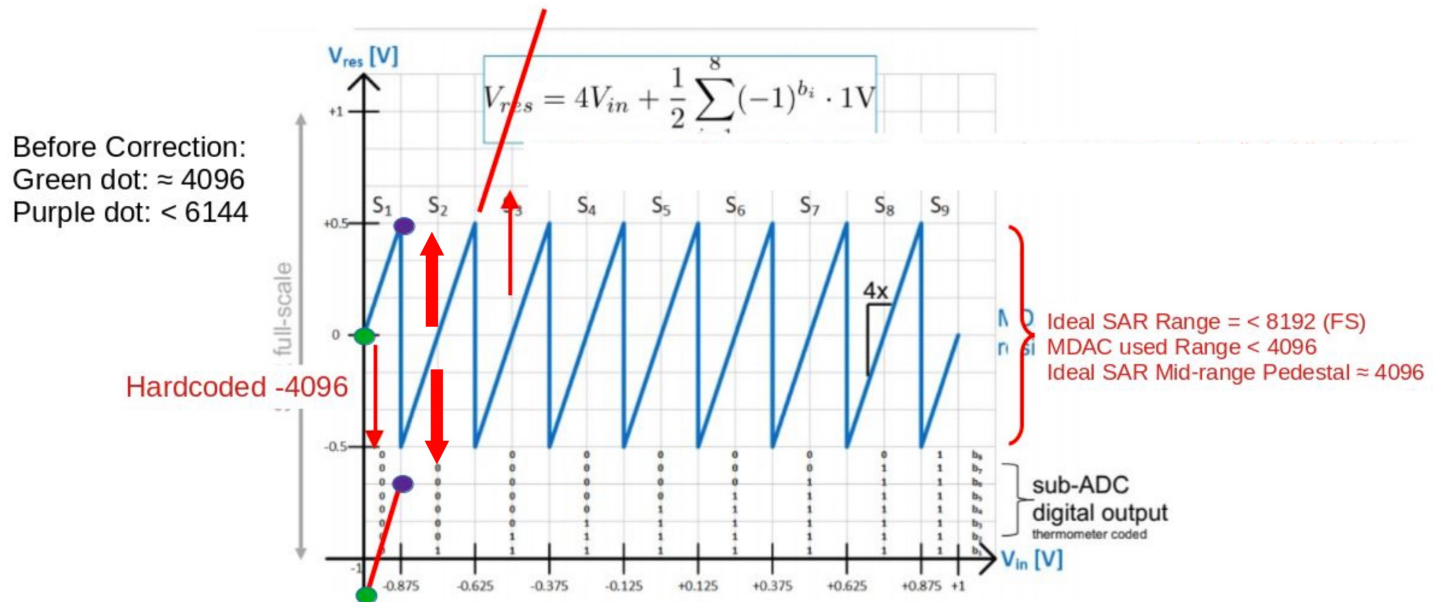
After Correction:

Green dot: ≈ 0

Purple dot: < 2048 → does **NOT** meet with bottom of S2
→ discontinuity cannot be calibrated by DDPU

Modification: Digital Correction

- Fix: Allow programmability in the MSB of correction constant S2. In two's complement, this is the sign bit. Allows S2 to move up **or** down.
Actual DDPU Correction,



By allowing S2 to move up or down, the DDPU digital code output will be continuous. S2 will have a programmable range equal to twice the designed range.